

Search Notes

Application/Control No.

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Examiner

José R. Díaz

Applicant(s)/Patent under
Reexamination

YUN ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	522, e23.013	2/6/2006	JRD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR